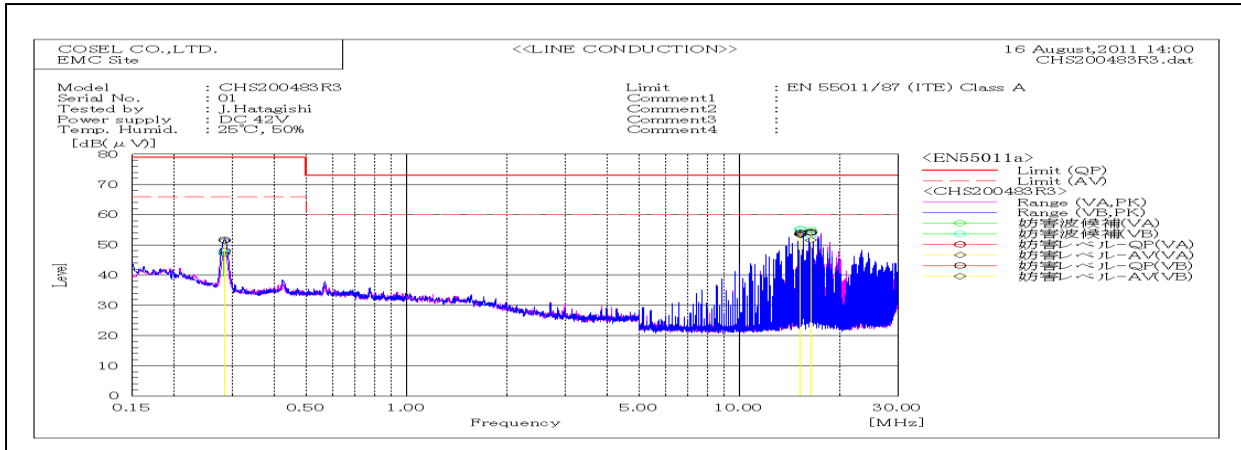
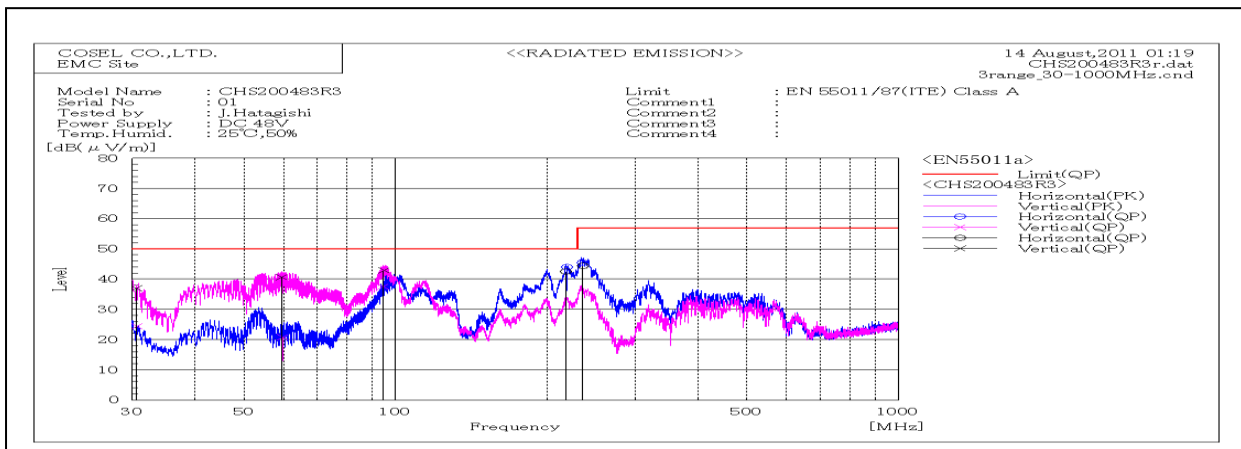


DATA SHEET		Date	16-Aug-11
Model	CHS200483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	J.Hatagishi



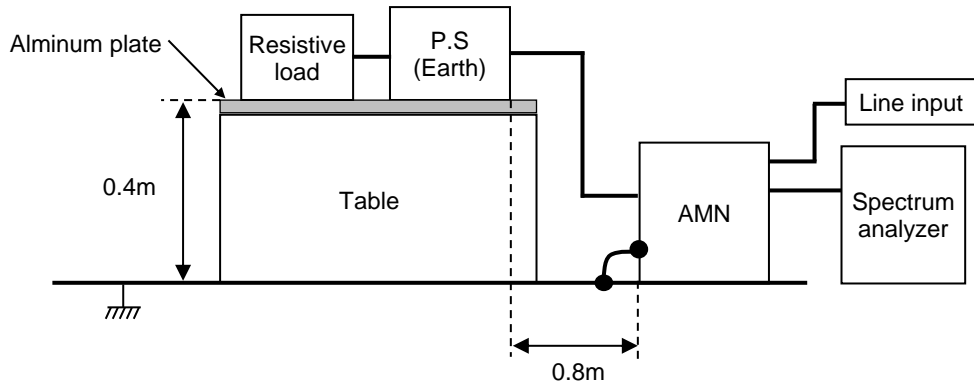
Frequency MHz	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.2844	VA	38	37	10	48	47	79	66	31	19	Pass
0.28413	VB	41.7	41.4	10	51.7	51.4	79	66	27.3	14.6	Pass
15.2394	VA	43	42.7	10.7	53.7	53.4	73	60	19.3	6.6	Pass
15.2404	VB	43.5	42.7	10.6	54.1	53.3	73	60	18.9	6.7	Pass
16.37795	VA	43.5	40.8	10.8	54.3	51.6	73	60	18.7	8.4	Pass
16.38325	VB	43.4	43.2	10.7	54.1	53.9	73	60	18.9	6.1	Pass



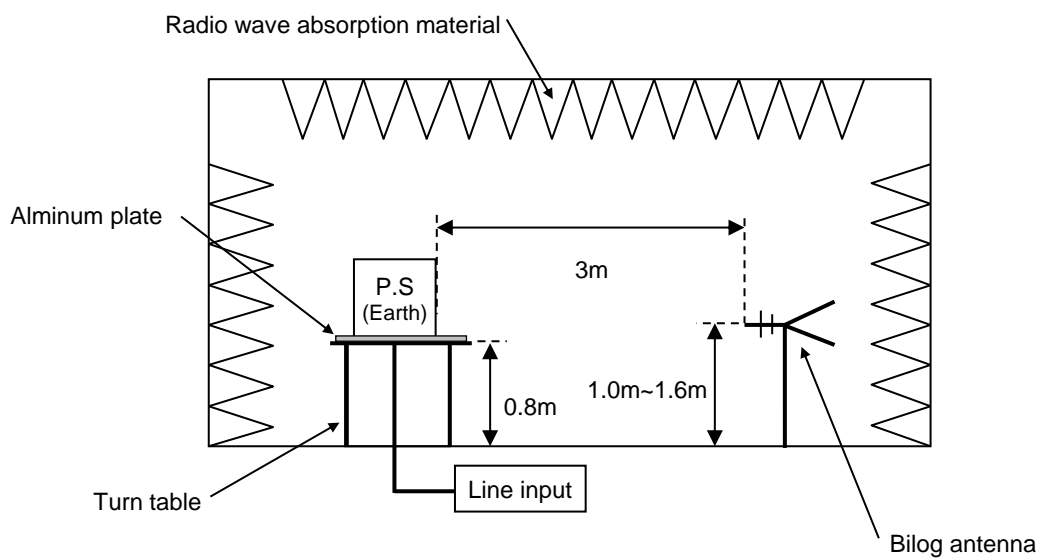
Frequency MHz	Polarization	Stability	Reading	Space Loss dB	Level	Limit	Margin dB	Pass/Fail	Height cm	Angle deg
			dB(uV)		dB(mW)	QP				
30.596	V	Stable	50.7	-13.7	37	50	13	Pass	104	4
59.382	V	Stable	66.8	-26.1	40.7	50	9.3	Pass	134	281
94.796	V	Stable	65.2	-22.3	42.9	50	7.1	Pass	102	245
218.353	H	Stable	63.4	-20.9	42.5	50	7.5	Pass	148	181
236.01	H	Stable	63.4	-19	44.4	57	12.6	Pass	125	170

DATA SHEET		Date	16-Aug-11
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	J.Hatagishi

1. Line conduction



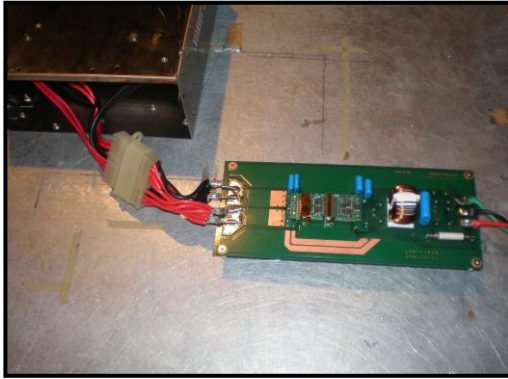
2. Radiated emission



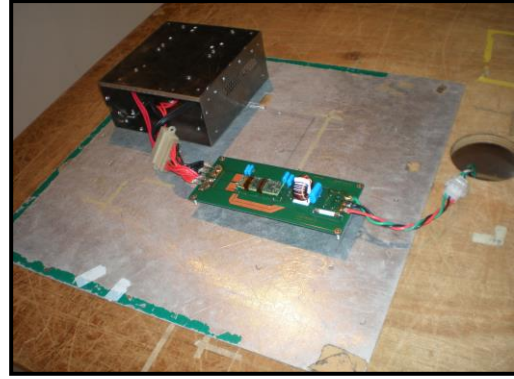
Test : EMI
 Model Name : CHS200 Series

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○ Testing circuitry

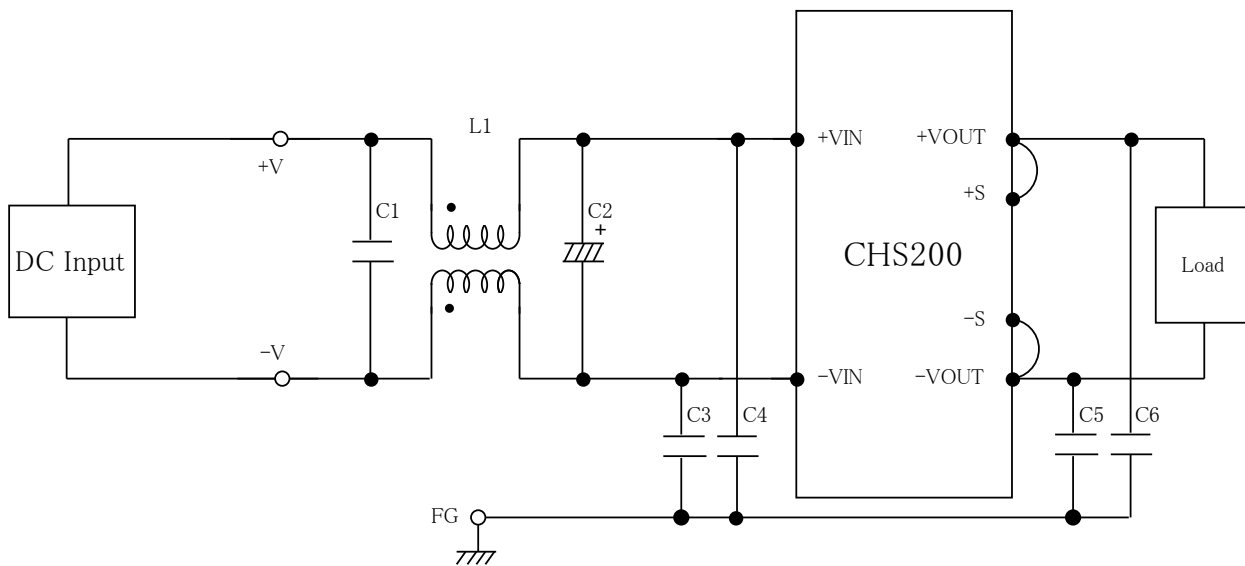


Fig.1 Testing circuitry

- L1 : 1mH SC-10-10J (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2 : 100V 100 μ F PWseries (nichicon)
- C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
- C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)